Supporting Information

Multifunctional Plasmonic Film for Recording Near-Field Optical Intensity

Brian J. Roxworthy,[†] Abdul M. Bhuiya,[†] V. V. G. Krishna Inavalli,[‡] Hao Chen,[‡] and Kimani C. Toussaint, Jr.^{*,‡}

[†] Department of Electrical and Computer Engineering, University of Illinois at Urbana-Champaign, Urbana, Illinois 61801, USA.

[‡]Department of Mechanical Science and Engineering, University of Illinois at Urbana-Champaign, Urbana, Illinois 61801, USA.

* email: <u>ktoussai@illinois.edu</u>



Figure S1: Angle-dependent reflectance spectra. Normalized theoretical reflectance curves calculated as a function of illumination angle of incidence for pBNAs exposed with a dosage of 0.1 mW μ m⁻². The Rayleigh anomaly causes sharp dips in reflected power, which appear as peaks in the normalized reflectance calculated using Equation 3 in the main text.



Figure S2: Axial optical forces: (a) Optical potential energy determined from the (b) optical forces on a 10-nm dielectric sphere (n = 1.59) calculated using the Maxwell stress tensor.